

Application of Thomas–Reiche–Kuhn Sum Rule to the Parametrization of JDOS of Hydrogenated Amorphous Silicon

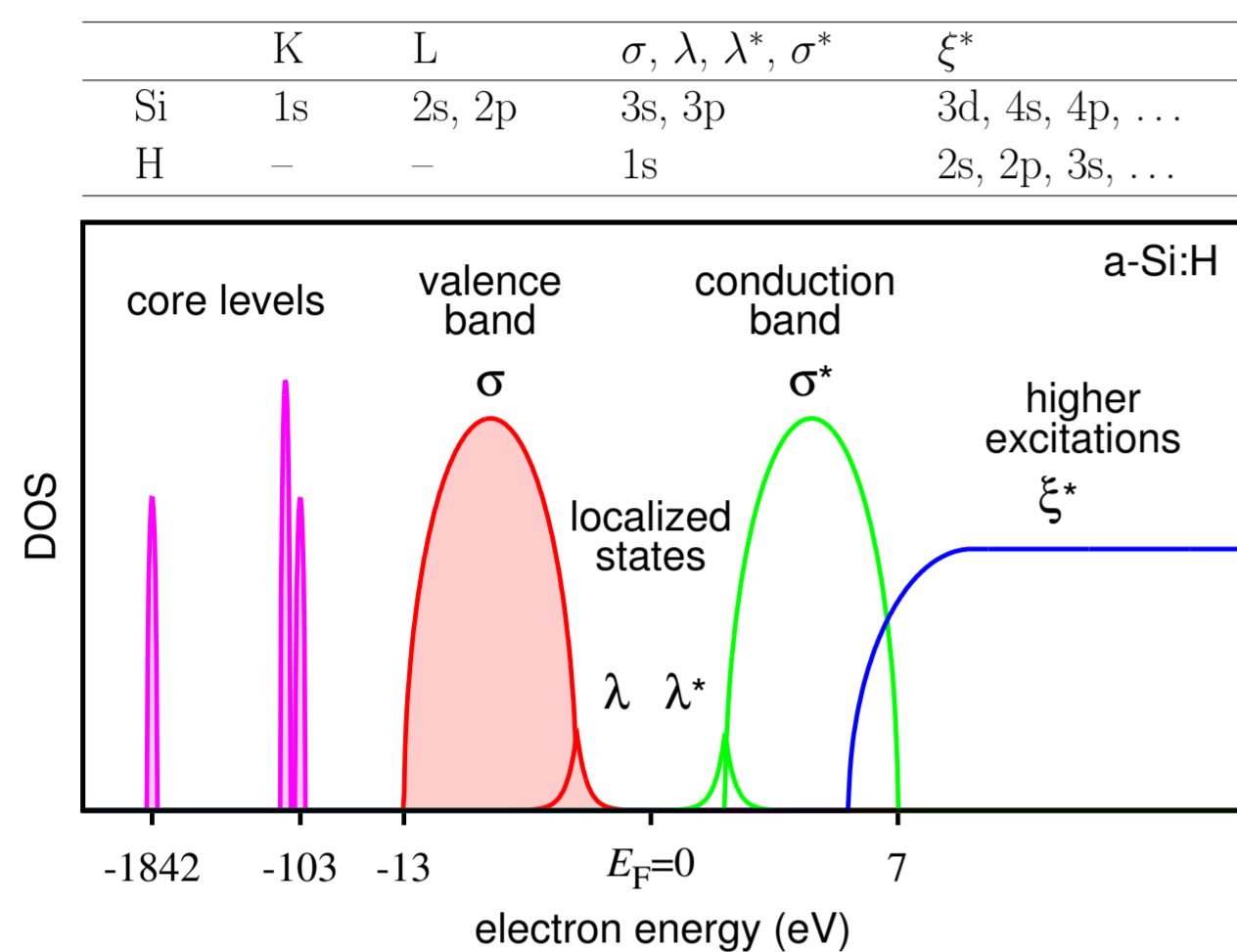


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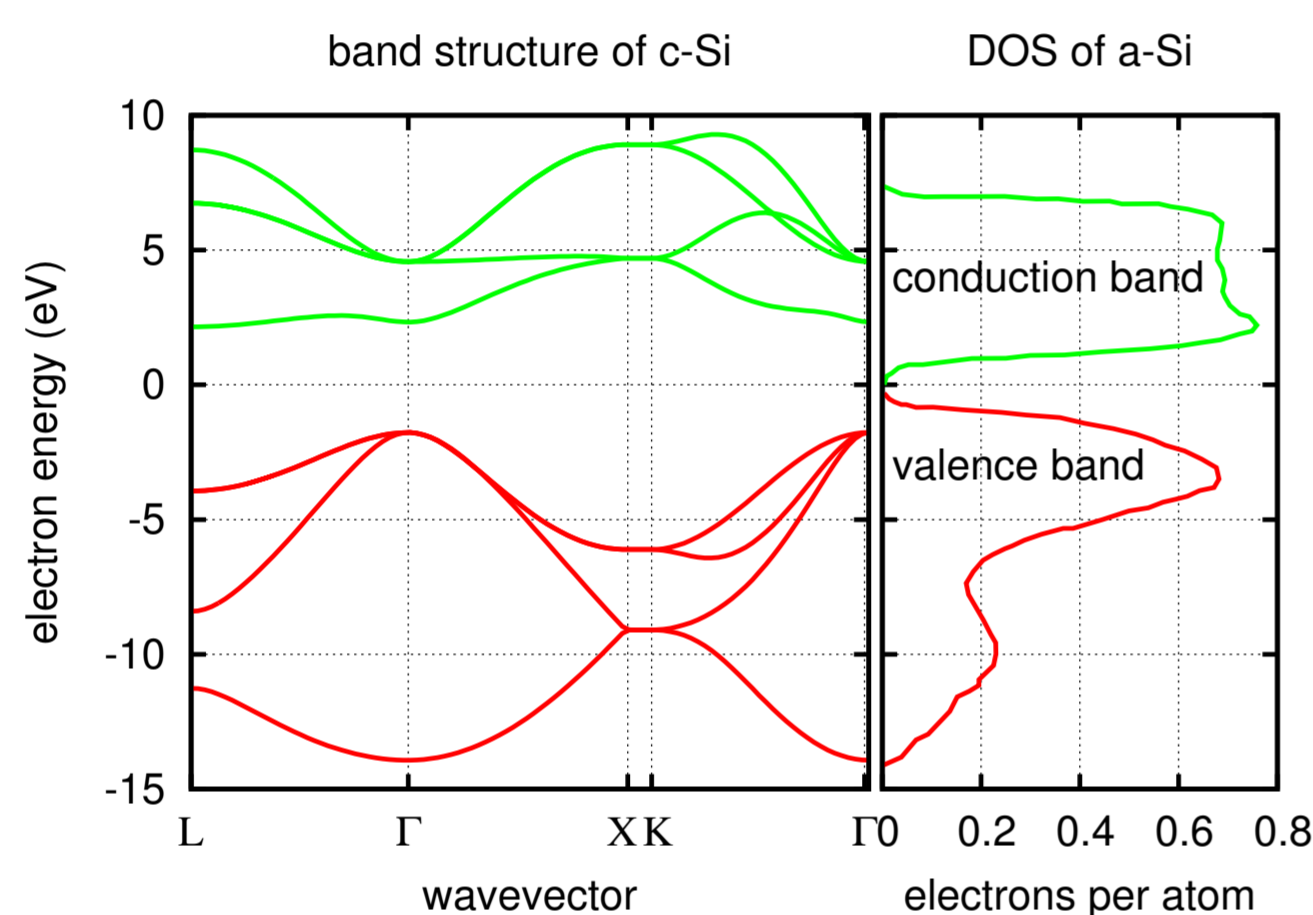
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Electronic structure

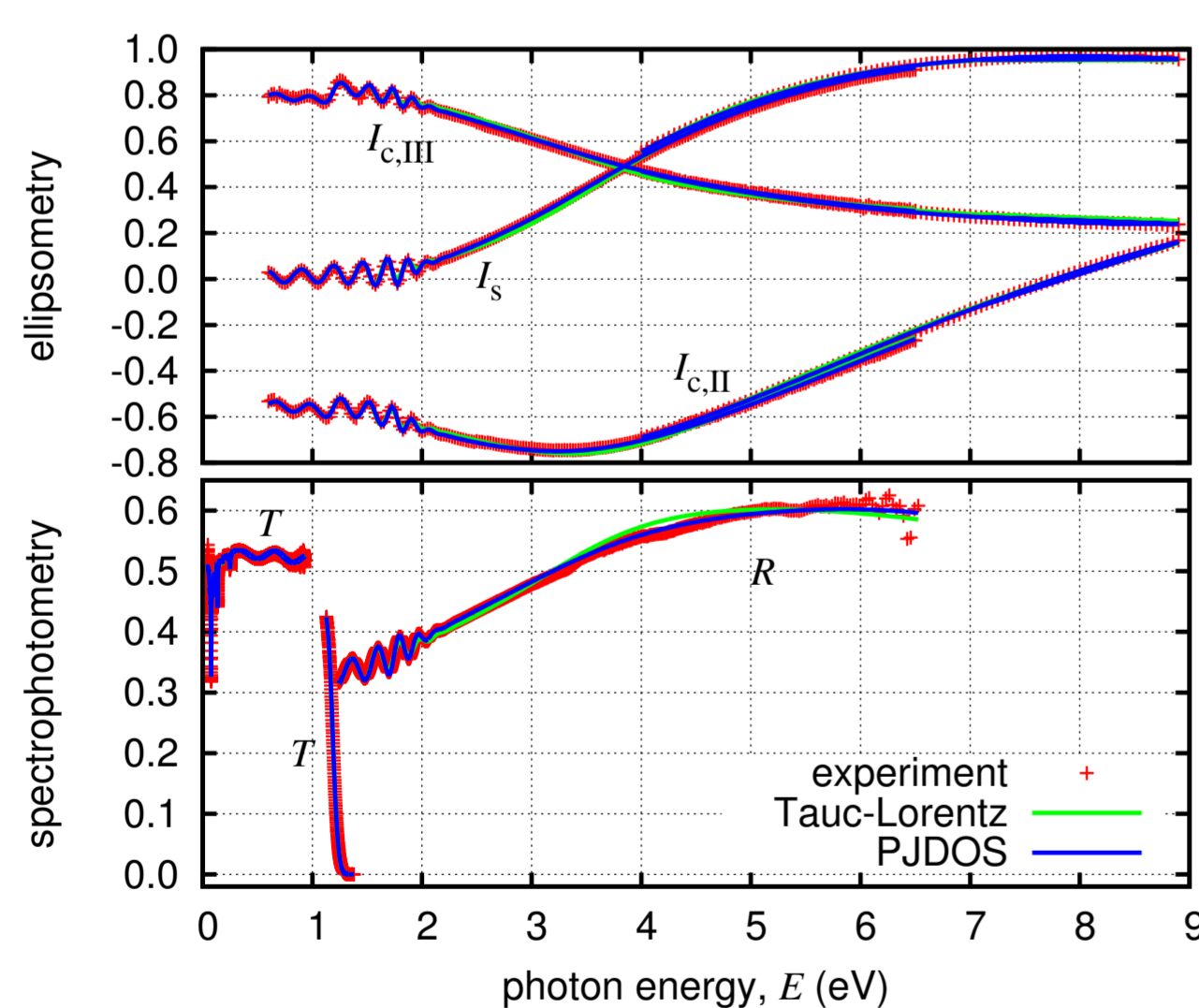


Schematic diagram of electronic structure of amorphous silicon.



Electronic structure of crystalline and amorphous silicon calculated using tight-binding method [1] and [2].

Experiment



Modeling

All individual contributions of the PJJDOS model are modeled using analytical Kramers–Kronig consistent functions.

Interband transitions $\sigma \rightarrow \sigma^*$ (IBTL5)

Combination of parabolic bands with Lorentzian function.

$$\varepsilon_i(E) = \frac{J(E)}{E^2} = \begin{cases} N_{\sigma\sigma} \frac{(|E| - E_g)^2 (|E| - E_h)^2}{CE[(E^2 - E_g^2)^2 + B_c^2 E^2]} & \text{for } E_g < |E| < E_h \\ 0 & \text{otherwise,} \end{cases}$$

where C is normalization constant chosen that the following holds:

$$N_{\sigma\sigma} = \int_0^\infty E \varepsilon_i(E) dE$$

The real part is calculated from Kramers–Kronig integral:

$$\varepsilon_r(E) - 1 = \frac{2}{\pi} \int_0^\infty \frac{X \varepsilon_i(X)}{X^2 - E^2} dX$$

It leads to combinations of **logarithmic** and **rational** functions similarly to the Tauc–Lorentz model (see poster devoted to DLC).

Excitations of electrons $\sigma \rightarrow \lambda^*$ and $\lambda \rightarrow \sigma^*$ – Urbach tail (UT4)

The absorption below the band gap is modeled using exponential Urbach tail smoothly extended by a second-order polynomial $P_2(E)$:

$$\varepsilon_i(E) = \frac{J(E)}{E^2} = \text{sgn}(E) \times$$

$$\begin{cases} \frac{N_{\sigma\lambda}}{CE^2} \left[\exp\left(\frac{E - E_g}{E_u}\right) - \exp\left(-\frac{E_g}{2E_u}\right) \right] & \text{for } \frac{E_g}{2} < |E| < E_g \\ \frac{N_{\sigma\lambda}}{CE^2} \left[P_2(E) - \exp\left(-\frac{E_g}{2E_u}\right) \right] & \text{for } E_g \leq |E| \leq E_h \\ \frac{N_{\sigma\lambda}}{CE^2} \left[\exp\left(\frac{E_h - E}{E_u}\right) - \exp\left(-\frac{E_g}{2E_u}\right) \right] & \text{for } E_h < |E| < E_h + \frac{E_g}{2} \\ 0 & \text{otherwise.} \end{cases}$$

Integrations leads to **exponential integral** functions in $\varepsilon_r(E)$.

Excitations of electrons $\sigma \rightarrow \xi^*$ (HET2)

$$\varepsilon_i(E) = \frac{J(E)}{E^2} = \begin{cases} 0 & \text{for } |E| \leq E_{g\xi} \\ N_{\sigma\xi} \frac{3E_{g\xi} (|E| - E_{g\xi})^2}{E^5} & \text{for } |E| > E_{g\xi} \end{cases}$$

$$\varepsilon_r(E) - 1 = N_{\sigma\xi} \frac{3E_{g\xi}}{\pi E^2} \left[a(E) \ln \left| 1 - \frac{E}{E_{g\xi}} \right| + b(E) \ln \left| 1 + \frac{E}{E_{g\xi}} \right| - c - \frac{d}{E^2} \right]$$

where

$$a(E) = -\frac{(E_{g\xi} - E)^2}{E^3}, \quad b(E) = \frac{(E_{g\xi} + E)^2}{E^3}, \quad c = \frac{2}{3E_{g\xi}}, \quad d = 2E_{g\xi}$$

Density of the valence electrons (optical electron density)

$$N_v = \int_0^\infty \sum_{j=\sigma,\lambda,k=\lambda^*,\sigma^*,\xi^*} E \varepsilon_{i,j \rightarrow k}(E) dE \quad (\text{eV}^2)$$

$$N_v = N_{\sigma\sigma} + N_{\sigma\lambda} + N_{\sigma\xi}$$

Excitations of core electrons K, L $\rightarrow \sigma^* + \xi^*$ (CEE2)

$$\varepsilon_i(E) = \frac{J(E)}{E^2} = \begin{cases} 0 & \text{for } |E| < E_k \\ N_k \frac{E_k}{E^3} & \text{for } |E| \geq E_k \end{cases}$$

$$\varepsilon_r(E) - 1 = \frac{N_k}{\pi E^3} \left[E_k \ln \left| \frac{E_k + E}{E_k - E} \right| - 2E \right]$$

Density of the K and L core electrons

$$N_K = 2N_v \frac{1 - C_H}{4 - 3C_H} \quad \text{and} \quad N_L = 8N_v \frac{1 - C_H}{4 - 3C_H}$$

where C_H is atomic concentration of hydrogen (for our sample $C_H = 0.11$)

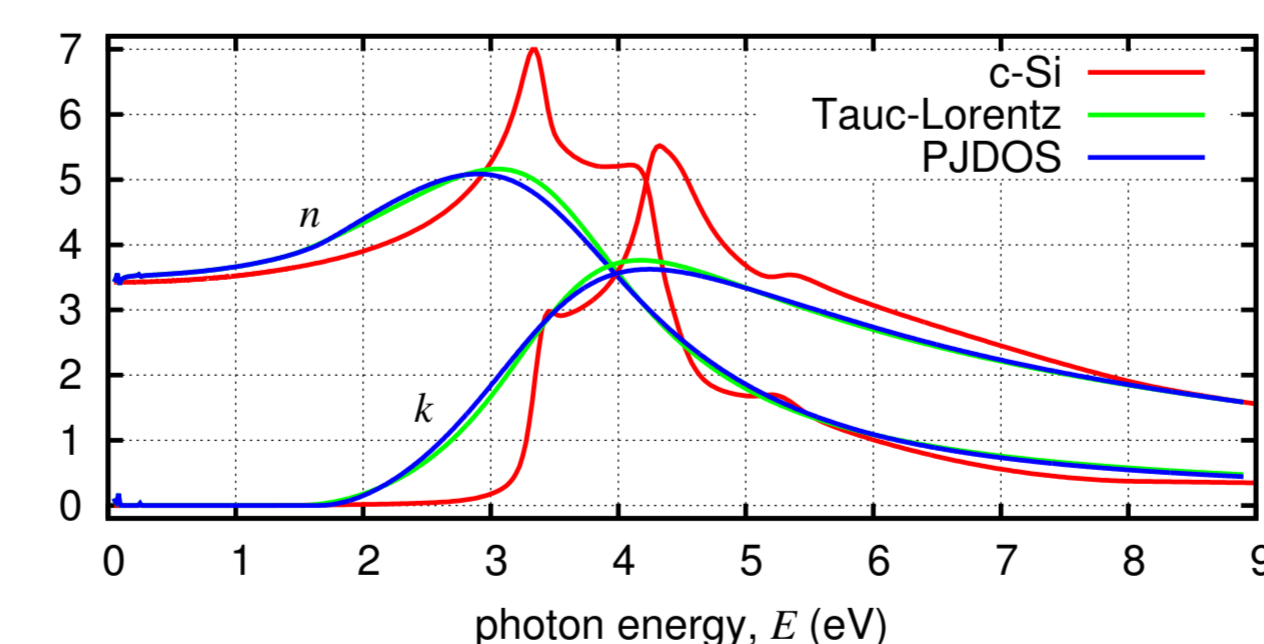
Phonon absorption peaks (GP3)

Modeled by Gaussian peaks leading to **Dawson integrals** in $\varepsilon_r(E)$.

Tauc-Lorentz model

For renormalized Tauc-Lorentz model see poster devoted to DLC.

Results



Optical constants of a-Si:H films determined using different models.

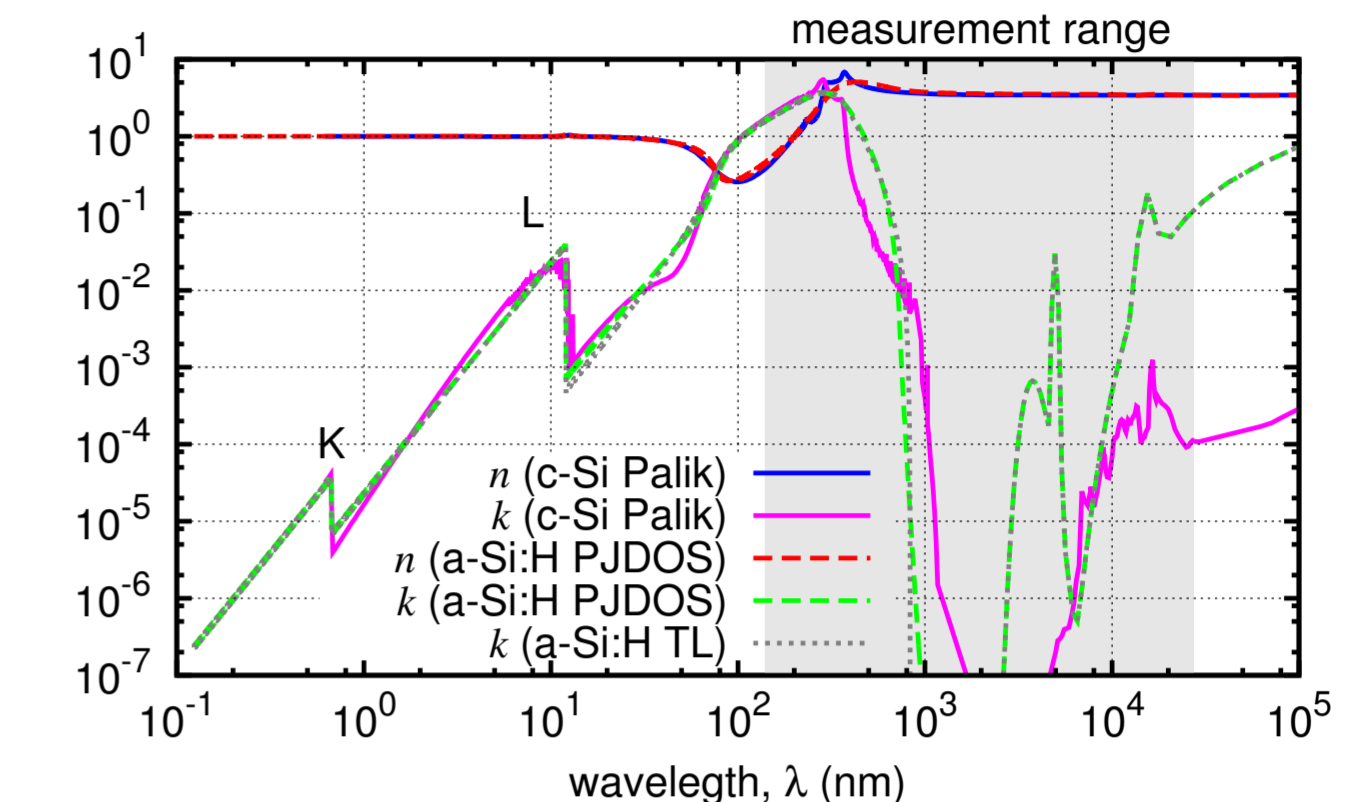
model	$N_{\sigma\sigma}$ (eV ²)	E_g (eV)	E_c (eV)	E_h (eV)	B_c (eV)	$N_{\sigma\xi}$ (eV ²)	$E_{g\xi}$ (eV)
Tauc-Lorentz	421.4	1.486	3.621	-	1.929	-	-
PJJDOS	316.0	1.669	3.587	20*	2.355	102.6	5.878

model	$N_{\sigma\lambda}$ (eV ²)	E_u (eV)	E_K (eV)	E_L (eV)	C_H	χ
Tauc-Lorentz	0	-	1.842*	103*	0.11*	2.38
PJJDOS	6.2	0.036	1.842*	103*	0.11*	1.38

* fixed parameter

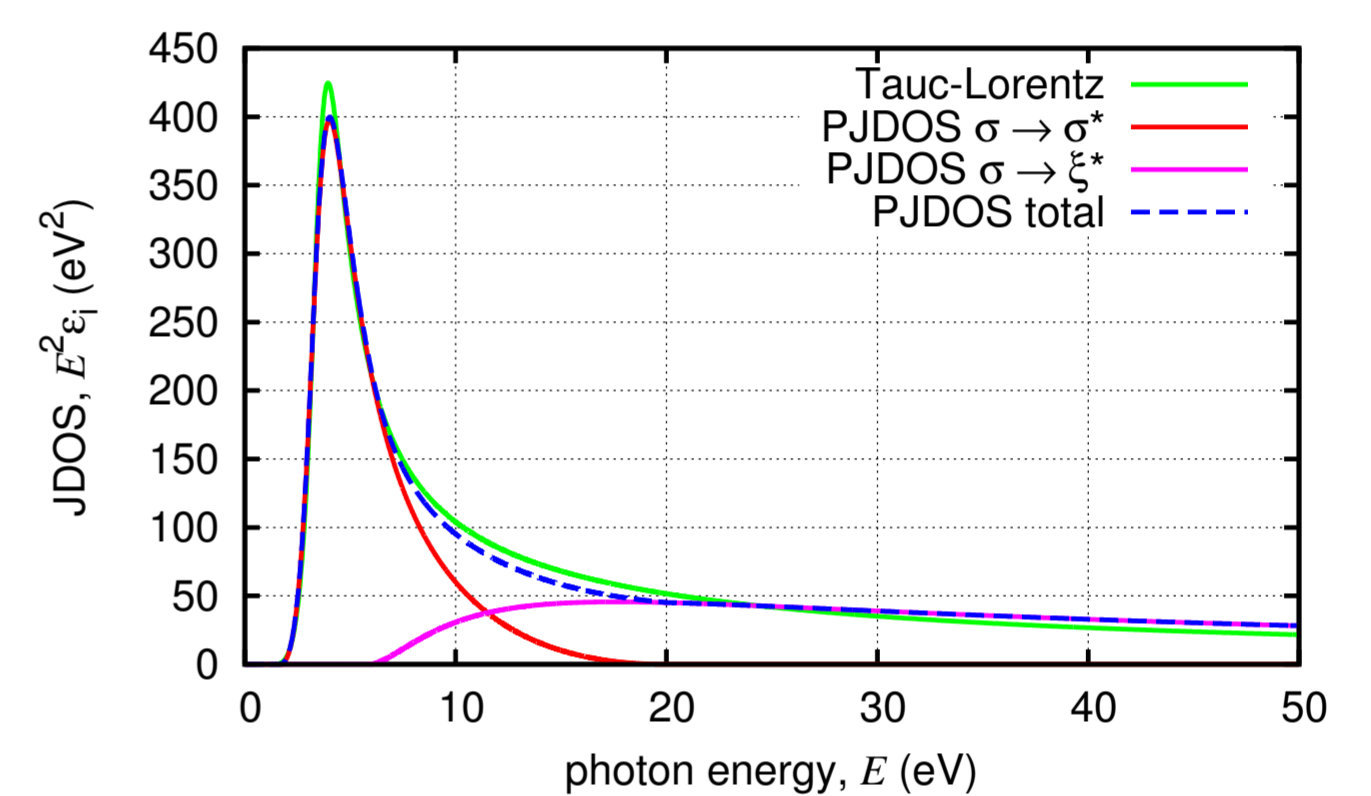
Quantity χ characterizes the disagreement between theoretical and experimental data (1 is optimum)

Comparison with c-Si



Log-log plot of optical constants of crystalline and amorphous silicon.

JDOS function of a-Si:H



Comparison of joint density of states determined using different models.

Total optical density of the electrons

$$N_e = N_v + N_K + N_L = N_v \frac{14 - 13C_H}{4 - 3C_H} \quad (\text{eV}^2)$$

Relation to plasma frequency ω_p

$$\text{for } E \rightarrow \infty, \quad \varepsilon_r(E) \approx 1 - \frac{2N_e}{\pi E^2} = 1 - \frac{(\hbar\omega_p)^2}{E^2} = 1 - \frac{\omega_p^2}{\omega^2}$$

$$N_e = \frac{\pi}{2} (\hbar\omega_p)^2$$

Optical density of atoms

$$N_a = \frac{N_e}{14 - 13C_H} = \frac{N_v}{4 - 3C_H} \quad (\text{eV}^2)$$

Real electron density

$$N_e = 4.617 \cdot 10^{26} N_e \quad (1/\text{m}^3)$$

Mass density of the a-Si:H films

$$\rho = N_a [A_{Si}(1 - C_H) + A_H C_H] u \quad (\text{kg}/\text{m}^3)$$

$$N_a = 4.617 \cdot 10^{26} N_a$$

- N_a density of atoms (1/m³)
- A_{Si} silicon atomic weight (28.09 g/mol)
- A_H hydrogen atomic weight (1.008 g/mol)
- u atomic mass unit (1.6605 · 10⁻²⁷ kg)

model	N_v (eV ²)	N_e (eV ²)	N_a (eV ²)	N_e (1/m ³)	N_a (1/m ³)	ρ (kg/m ³)
Tauc-Lorentz	421.4	1443	114.8	6.664 · 10 ²⁹	5.302 · 10 ²⁸	2211
PJJDOS	424.8	1455	115.7	6.718 · 10 ²⁹	5.344 · 10 ²⁸	2228

Compare with density of the c-Si: $\rho = 2329 \text{ kg}/\text{m}^3$

Acknowledgments

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References

- D. J. Chadi, M. L. Cohen, Phys. Status Solidi B 68 (1975) 405–419.
- H. C. Kang, J. Non-Cryst. Solids 261 (2000) 169–180.